EP4 Microscopic Imaging for Nanomaterials Characterization Technical Talk and Live Demonstration

November 7, 9:00 AM
Georgia Institute of Technology
Pettit Microelectronics Building 102 A&B
791 Atlantic Drive
Atlanta, GA 30332-1000

ACCURION
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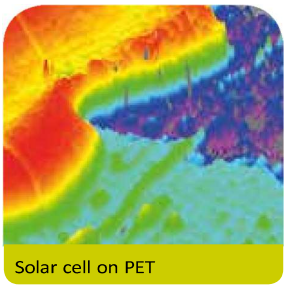
The need to characterize the physical and optical properties of structured thin films and 2-D materials is increasing. Ellipsometry is a useful technique for large area sample measurements but conventional systems of this type are limited in lateral resolution by the illuminating spot size, and by the fact that measurements are made at only one location at a time. The EP4 Microscopic Imaging ellipsometer uses Auto-nulling, a microscope objective, and a two dimensional CCD array to overcome these limitations.

The EP4 system can resolve features as small as one micron and collect data from over a million sample areas simultaneously. It has been shown to be very effective for studying structured or patterned thin films, and 2-D materials research including anisotropic nanomaterials characterization.

An introductory technical talk will begin at 9:00am, followed by a live video conference at 10:30 demonstrating the operation of the EP4 on a variety of samples, including Graphene flake samples, and samples provided in advance by researchers associated with Georgia Tech.

To submit a sample (bio, polymers, thin films, etc.) in advance for processing during the live demonstration via video conference, or if you have any questions regarding the seminar and demonstration, contact Eric Woods:
eric.woods@ien.gatech.edu


SAM


Solar cell on PET

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